

TS18H

FEATURES

- Small size
- Excellent Break down voltage, low DF
- Suit to re-flow soldering, wave soldering, hand soldering

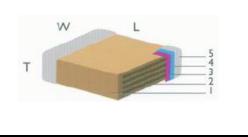
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TS18H SMD is widely used in Analog & Digital Modems, LAN/WAN Interface, Lighting Ballast Circuits, Voltage Multipliers, DC-DC Converter, Back-lighting Inverters.



OUTSIDE DIMENSION

Ту	pe			(mm)	
British	Metric	L	W	T max	
expression	expression	(mm)	(mm)	(mm)	
0603	1608	1.52 ± 0.25	0.76 ± 0.25	1.01	W
0805	2012	2.00 ± 0.25	1.25 ± 0.25	1.45	
1206	3216	3.20 ± 0.30	1.60 ± 0.30	1.90	- 4
1210	3225	3.20 ± 0.40	2.50 ± 0.30	2.80	i i
1808	4520	4.50 ± 0.40	2.00 ± 0.25	2.80	2
1812	4532	4.50 ± 0.40	3.20 ± 0.40	3.10	
2220	5750	5.70 ± 0.40	5.00 ± 0.40	3.00	
2225	5763	5.70 ± 0.50	6.30 ± 0.50	6.20	



Coefficient

Parameter	NPO Temperature Wave		X7R Temperature Wave		
Temperature Coefficient	30 PPM -30 -55℃ -25 0℃ 25 50	75 100125℃	+15% 0% -15% -30%	-25 0°C 25 50	75 100125°C
Dissipation Factor	DF≤0.15%		DF≤2.50%		
Aging	None		≤2.5% decade hour		
Insulation Resistance	≥100GΩ		≥500ΩF OR 50	GΩ	
Dielectric Strength	Rated Voltage Test Voltage Ur=100V 2.5Ur 200V≤Ur≤1000V 1.5Ur			Time $60 \pm 5S$ $60 \pm 5S$	
•				(10.7 ± 0.5)	



S P	E	7	I F	Ι	C	A	T	I	0	N	S
Item		Specifications					T	est Method			
	Class I	NPO:	-55 ~ +125℃								
Operating		X7R:	-55 ~ +125℃								
Temperature	Cl II	X5R:	X5R: -55 ~ +85°C Y5V: -30 ~ +85°C								
Range	Class II	Y5V:									
		Z5U:	Z5U: +10 ~ +85℃								
Tolerance	±5%, ±10% ±2	20%									
Appearance	No visual defec	ets			Visual inspe	ectio	on				
	Shou		d be within the	specified	Capacitance	2	Test Frequency	Test Volta	ge T	'empe	rature
	Class I	Class I toleran	nce		≤1000pF		1MHz±10%	1.0±0.2Vrn	•		
Capacitance					>1000pF		1KHz±10%	1.0±0.2 VIII	iis		
	Class II	Shoul	Should be within the specified tolerance		≤10μF		1KHz±10%	1.0±0.2Vrn	 		2℃
					>10µF		120±24Hz	0.5±0.1Vrn			
		torcra			Z5U		1.0±0.1KHz	0.5±0.05Vr	ms		
	Class I		≤0.15%								
Dissipation		X7R ≥50V			25V	16	V	Test Method: The same as			
Factor		X5R	≤2.5%		€.35%	≤3.5% "Capacitance"			c as		
(D.F.)	Class II	Y5V	≤7.0% (C<1.0μF	7)	≤12.5%	≤1	12.5%	Capacitairee			
		Z5U	≤9.0% (C≥1.0μ	F)							
		C≤10	OnF, Ri≥5000	0 M Ω	Rated	,	Tes Voltage	Duration	Charge/D	isch	
	Class I	Class I C>10nF, Ri* $C_R \ge 50$		600ΩF	Voltage		Duranton	arge Cur	rent		
		X7R	C≤25nF, Ri	\geqslant							Temper
Insulation		21/10	10000ΜΩ		Ur<500V	Ur		60 ± 5 sec ≤50			ature:25
Resistance		X5R	C>25nF, Ri	$*C_R>$					(00 III I		± 2℃
(I.R.)	Class II	$100\Omega F$									Humidit
	C1055 II	Y5V	C≤25nF, Ri	.≥							y:<75%
		13 V	4000ΜΩ		Ur<500V	50	0V	60±5 sec	≤50 mA		
	Z5U	Z5U	C>25nF, Ri	$*C_R>$	2- 200.		- /	32 - 3 350	120 1111		
			100ΩF								



S P	E C	I F	\mathbf{C}	A	T I	0	N S	
Item	S	Specifications			Test Method			
			Rated Voltage	Test Voltage	Duratio	on	Charge/Discha rge Current	
5.1			Ur<200V	2.5Ur	1~5sec	2.		
Dielectric Withstanding Voltage	No breakdown		200V≤Ur ≤ 1000V	1.5Ur	1~5sec.		≤50mA	
(D.W.V.)	or visual defects		Ur> 1000V	1.2Ur	1~5sec	c.		
			Dielectric withstanding voltage testing may requires immersion of the capacitor in a isolation fluid, at test voltage over 2000Vdc.					
	Class I		Perform a heat temperature at 150+0/-10°C for 1hrs,then place room temp. for 24±2hrs.					
Capacitance		NPO:0±30ppm/°C	According to the following sequence, measure the capacitance after temperature stabilize for 30min . ($\triangle C$ based on T3)					
Temperature			Step		Temperature (°C)			
Characteristic /		X7R:≤±15%	T1 25±2					
Coefficient	Class II	X5R:≤±15%	T2 Low-category temp.					
		Y5V:+22%~-82%	Т3		25±2			
		Z5U:+22%~-56%	T4		High-category temp. 25±2			
			T1					
	N 16 - > 00		Preheating Conditions:80~120°C;10~30sec.					
Solderability	·	No defects, ≥90% of each terminal should		Solder Temperature: 245±5°C Immersing Speed:25±0.25mm/s				
	be covered with	iresn solder	Duration: 2±0.5sec.					
Adhesive			Applied Force:5N 5N					
Strength of	Appearance: No	visible damage.	Duration:10	±1sec.				
Termination		<u> </u>	Speed:1mm/	/sec	cec Cap			



S P	E C	I F I	\mathbf{C}	A T I	O N S			
	A mm a a man a a	No crack or marked	Solder the capacit	or on the	20 150			
Resistance	Appearance	defects should occur.	test jig,using a eut	Pressurize				
to Flexure	△C/C	Class I : ≤±5%	solder.Then apply	a force				
Stresses			in the direction.		Flexump:≤1			
Stresses		Class II: ≤±10%	Deflection:1mm		Capaditance meter 45 45			
			Speed: 1mm/sec	17.				
		No defects,≥90% of each						
	Appearance	terminal should be covered						
		with fresh solder						
		Class I: $\leq \pm 0.5\%$ or						
	△C/C	±0.5pF	capacitor in a eutectic solder at 265±5°C for 5±1 seconds. Store at room temperature for 24±2 hours before measureing electric properties.					
Resistance		(whichever is larger)						
to Soldering		Class II:						
Heat		X7R X5R: -5~+10%						
		Y5V Z5U: -10∼+20%						
	D.F.	Meets Initial Values						
		(As Above)						
		Meets Initial Values						
	1.14.	(As Above)						
	Appearance	No visual defect	Perform a heat ten	nperature at 150+0/-10°	+0/-10°C for 1hrs,then place room			
	пррешинее	110 Visual defect	temp. for 24±2hrs.					
		Class I: ≤±1% or	Fix the capacitor t	o the supporting iig Per	rform the five cycles according			
		±1pF	-	11 030	llowing table.Store at room			
	△C/C	(whichever is larger)						
Temperature	<u> </u>	Class II:	temperature for 24±2 hours before measureing electric properties.					
Cycle		X7R X5R ≤±10%	Step	Temperature ($^{\circ}$ C)	Time (min.)			
		Z5U Y5V ≤±20%	1	Low-category temp	. 30			
	D.F.	Meets Initial Values	2	25±2	3			
	D.I.	(As Above)	3	High-category temp	o. 30			
	I.R.	Meets Initial Values	4	25±2	3			
		(As Above)	7	23.12	3			



S P	E C	I F I	C A	T I	O N S					
	Appearance	No visual defect								
	∆C/C	Class I: ≤±2% or								
		±1pF								
		(whichever is larger)								
	∠C/C	Class II:								
		X7R X5R ≤±10%	X5R ≤±10%							
Lumidity		Z5U Y5V ≤±30%	Z5U Y5V $\leq \pm 30\%$ Let the capacitor sit at $40\pm 2^{\circ}$ C and 90 to 95% humidity for $500+24$							
Humidity Steady State	D.F.	≤Initial Values *2	hours.Remove and let sit	for 48±2 hours at re	oom temperature before					
Steady State	D. F.	(See Above)	measureing electric prope	erties.						
	I.R.	ClassI:Ri≥2500MΩor								
		Ri*CR>25ΩF								
		(whichever is smaller)								
		ClassII:Ri≥1000MΩor								
		Ri*CR>25ΩF	$i*CR>25\Omega F$							
		(whichever is smaller)								
	Appearance	No visual defect	Rated Voltage	Applied	Charge/Discharge					
		No visual defect	Nated Voltage	Voltage	Current					
		Class I: $\leq \pm 2\%$ or ± 1 pF	Ur<500V	2Ur						
		(whichever is larger)	$500V \leqslant Ur \leqslant 1000V$	$500V \leqslant Ur \leqslant 1000V \qquad \qquad 1.5Ur$						
	△C/C	Class II:	Ur>1000V	1.2Ur	≤50mA					
		X7R X5R ≤±20%	C1 > 1000 V	1.201						
		Z5U Y5V ≤±30%								
Loading Life	D.F.	≤Initial Values *2								
		(See Above)								
		ClassI:Ri≥4000MΩor								
		Ri*CR>40ΩF								
	I.R.	(whichever is smaller)								
		ClassII:Ri≥2000MΩor								
		Ri*CR>50ΩF								
		(whichever is smaller)								



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Precautions on the use of MLCC:

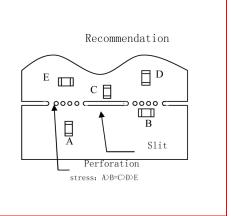
1.eneral Precautions On The Use Of MLCC:

The Multi-layer Ceramic Capacitors MLCC may fail when subjected to severe conditions of electrical environment and manchanical stress beyond the specified "rating" and specified condition in the specification. Following the precautions for satefy.

PCB Design

The amount of solder applied can affect the ability of chips to withstand mechanical stresses, which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads, which determines the amount of solder necessary to form the fillets.

When designing the position of solder pads and SMD capacitors, it should be carefully performed to minimize stress.SMD capacitors should be located to minimize any possible mechanical stresses from board warp or deflection.



3. Considerations For Automatic Placement

If the lower limit of the pick-up nozzle is low, too much force may be imposed on the capacitors, causing damage. To avoid this, the following points should be considered before lowering the pick-up nozzle:

The lower limit of the pick-up nozzle should be adjusted to the surface level of the PC board after correcting for deflection of the board.

The pick-up pressure should be adjusted between 1 and 3 N static loads.

To reduce the amount of deflection of the board caused by impact of the pick-up nozzle, supporting pins of back-up should be used the under PC board.

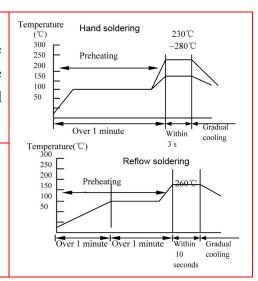


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4. Soldering

The ceramic section and metal section combine to the MLCC. As the poor heat conductivity of the ceramic section , ceramic chip capacitors are susceptible to thermal shock when exposed to rapid or concentrated heating or rapid cooling, especialy for large s

When hand soldering, use a soldering iron with a maximum power of 25W and a maximum tip diameter of 1.0mm. The soldering iron should touch the capacitor directly.



5.Cleaning

The temperature difference between the components and cleaning process should not be greater than 100°C. In the case of ultrasonic cleaning, too much power output can cause excessive vibration of the PC board which may lead to the cracking of the capacitor or the soldered portion, or decrease the terminal electrodes' strength, thus the following condition

Ultrasonic output: Below20W/L Ultrasonic frequency: Below 40KHZ Ultrasonic washing period: 5min or less

6.Breakaway PC Boards

When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of twisting to board.1. Be careful not to subject the capacitors to excessive mechanical shocks.

Board separation should not be done manually, but by using the appropriate devices.

7. Storage Conditions

To maintain the solderability of terminal electrodes and to keep the packaging material in good condition, recommended conditions as the following:

Temperature: $5-40^{\circ}C$; Humidity: 20-70% RH

Even though MLCC are stored in a good condition, the solderability of MLCC terminal electrodes will decrease as time goes by, so components should be used within 6 months from the time of delivery.



TS18H

Capacitance & Voltage

Size	Rated	Capacitance Range (pF)		Size	Rated	Capacitance Range (pF)		
5120	Voltage	NPO	X7R		Voltage	NPO	X7R	
0.402	100V	1 ~ 470	100~22 000		100V	3.3~8 200	220~470 000	
0603	200V	1~330	100~8 200		200V	3.3~6 800	220~180 000	
	100V	1~1 000	100~56 000		500V	3.3~4 700	220~150 000	
0805	200V	1~820	100~27 000	1812	1000V	3.3~1 200	220~27 000	
	500V	1~560	100~12 000		2000V	3.3~390	220~12 000	
	100V	1.5~3 300	100~220 000		3000V	3.3~270	220~5 600	
	200V	1.5~2 200	100~120 000		4000V	3.3~220	220~1 500	
1206	500V	1.5~1 000	100~56 000		100V	10~12 000	470~1000 000	
	1000V	1.5~680	100~12 000		200V	10~8 200	470~1000 000	
	1000V	1.5~10	100~5 600	2225	500V	10~5 600	470~470 000	
	100V	2~5 600	150~330 000		1000V	10~2 700	470~68 000	
	200V	2~3 900	150~150 000		2000V	10~1 000	470~33 000	
1210	500V	2~2 200	150~100 000		3000V	10~680	470~4 700	
	1000V	2~820	150~15 000		4000V	10~560	470~3 900	
	2000V	2~470	150~8 200		100V	10~56 000	470~2200 000	
	100V	2~3 900	150~390 000		200V	10~47 000	470~2200 000	
	200V	2~3 000	150~180 000		500V	10~12 000	470~1000 000	
1000	500V	2~1 800	150~120 000	3035	1000V	10~10 000	470~390 000	
1808	1000V	2~820	150~22 000		2000V	10~5 600	470~270 000	
	3000V	2~150	150~2 700		3000V	10~3 900	470~8 200	
	4000V	2~100	150~1 000		4000V	10~560	470~3 000	

Note: Specification are subject to change without notice. For more detail and update, please visit our website.